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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

| | |
|--------------------------------|---|
| Product Status | Active |
| Number of LABs/CLBs | - |
| Number of Logic Elements/Cells | - |
| Total RAM Bits | 110592 |
| Number of I/O | 97 |
| Number of Gates | 600000 |
| Voltage - Supply | 1.14V ~ 1.575V |
| Mounting Type | Surface Mount |
| Operating Temperature | -40°C ~ 100°C (TJ) |
| Package / Case | 144-LBGA |
| Supplier Device Package | 144-FPBGA (13x13) |
| Purchase URL | https://www.e-xfl.com/product-detail/microchip-technology/a3p600l-1fgg144i |

1 – FPGA Array Architecture in Low Power Flash Devices

Device Architecture

Advanced Flash Switch

Unlike SRAM FPGAs, the low power flash devices use a live-at-power-up ISP flash switch as their programming element. Flash cells are distributed throughout the device to provide nonvolatile, reconfigurable programming to connect signal lines to the appropriate VersaTile inputs and outputs. In the flash switch, two transistors share the floating gate, which stores the programming information (Figure 1-1). One is the sensing transistor, which is only used for writing and verification of the floating gate voltage. The other is the switching transistor. The latter is used to connect or separate routing nets, or to configure VersaTile logic. It is also used to erase the floating gate. Dedicated high-performance lines are connected as required using the flash switch for fast, low-skew, global signal distribution throughout the device core. Maximum core utilization is possible for virtually any design. The use of the flash switch technology also removes the possibility of firm errors, which are increasingly common in SRAM-based FPGAs.

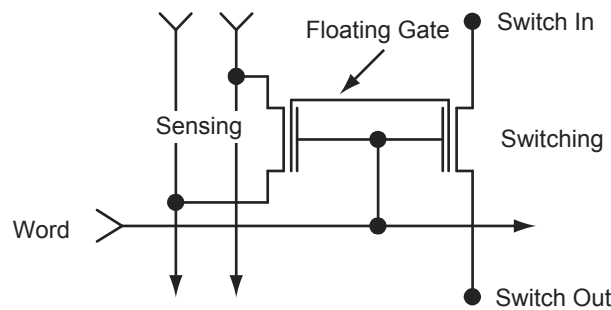


Figure 1-1 • Flash-Based Switch

Core Architecture

VersaTile

The proprietary IGLOO and ProASIC3 device architectures provide granularity comparable to gate arrays. The device core consists of a sea-of-VersaTiles architecture.

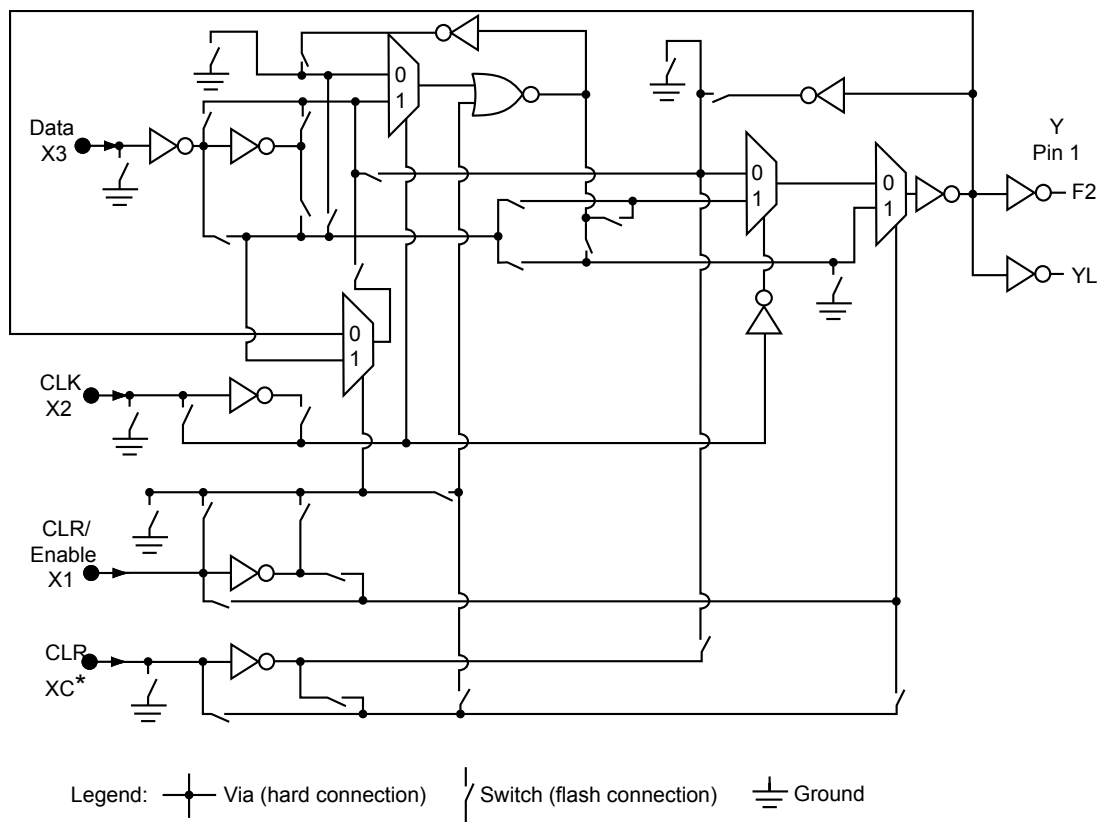
As illustrated in Figure 1-8, there are four inputs in a logic VersaTile cell, and each VersaTile can be configured using the appropriate flash switch connections:

- Any 3-input logic function
- Latch with clear or set
- D-flip-flop with clear or set
- Enable D-flip-flop with clear or set (on a 4th input)

VersaTiles can flexibly map the logic and sequential gates of a design. The inputs of the VersaTile can be inverted (allowing bubble pushing), and the output of the tile can connect to high-speed, very-long-line routing resources. VersaTiles and larger functions can be connected with any of the four levels of routing hierarchy.

When the VersaTile is used as an enable D-flip-flop, SET/CLR is supported by a fourth input. The SET/CLR signal can only be routed to this fourth input over the VersaNet (global) network. However, if, in the user's design, the SET/CLR signal is not routed over the VersaNet network, a compile warning message will be given, and the intended logic function will be implemented by two VersaTiles instead of one.

The output of the VersaTile is F2 when the connection is to the ultra-fast local lines, or YL when the connection is to the efficient long-line or very-long-line resources.



* This input can only be connected to the global clock distribution network.

Figure 1-8 • Low Power Flash Device Core VersaTile

2 – Flash*Freeze Technology and Low Power Modes

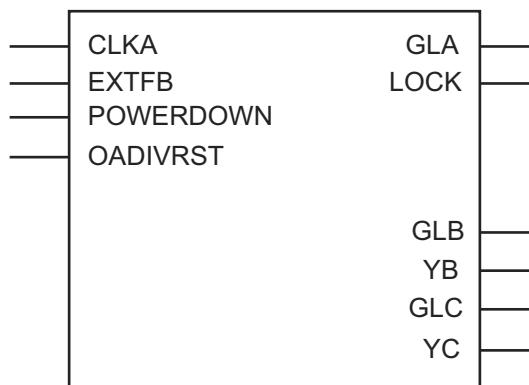
Flash*Freeze Technology and Low Power Modes

Microsemi IGLOO,[®] IGLOO nano, IGLOO PLUS, ProASIC[®]3L, and Radiation-Tolerant (RT) ProASIC3 FPGAs with Flash*Freeze technology are designed to meet the most demanding power and area challenges of today's portable electronics products with a reprogrammable, small-footprint, full-featured flash FPGA. These devices offer lower power consumption in static and dynamic modes, utilizing the unique Flash*Freeze technology, than any other FPGA or CPLD.

IGLOO, IGLOO nano, IGLOO PLUS, ProASIC3L, and RT ProASIC3 devices offer various power-saving modes that enable every system to utilize modes that achieve the lowest total system power. Low Power Active capability (static idle) allows for ultra-low power consumption while the device is operational in the system by maintaining SRAM, registers, I/Os, and logic functions.

Flash*Freeze technology provides an ultra-low power static mode (Flash*Freeze mode) that retains all SRAM and register information with rapid recovery to Active (operating) mode. IGLOO nano and IGLOO PLUS devices have an additional feature when operating in Flash*Freeze mode, allowing them to retain I/O states as well as SRAM and register states. This mechanism enables the user to quickly (within 1 μ s) enter and exit Flash*Freeze mode by activating the Flash*Freeze (FF) pin while all power supplies are kept in their original states. In addition, I/Os and clocks connected to the FPGA can still be toggled without impact on device power consumption. While in Flash*Freeze mode, the device retains all core register states and SRAM information. This mode can be configured so that no power is consumed by the I/O banks, clocks, JTAG pins, or PLLs; and the IGLOO and IGLOO PLUS devices consume as little as 5 μ W, while IGLOO nano devices consume as little as 2 μ W. Microsemi offers a state management IP core to aid users in gating clocks and managing data before entering Flash*Freeze mode.

This document will guide users in selecting the best low power mode for their applications, and introduces Microsemi's Flash*Freeze management IP core.



Note: OADIVRST exists only in the Fusion PLL.

Figure 3-15 • PLLs in Low Power Flash Devices

You can use the `syn_global_buffers` attribute in Synplify to specify a maximum number of global macros to be inserted in the netlist. This can also be used to restrict the number of global buffers inserted. In the Synplicity 8.1 version or newer, a new attribute, `syn_global_minfanout`, has been added for low power flash devices. This enables you to promote only the high-fanout signal to global. However, be aware that you can only have six signals assigned to chip global networks, and the rest of the global signals should be assigned to quadrant global networks. So, if the netlist has 18 global macros, the remaining 12 global macros should have fanout that allows the instances driven by these globals to be placed inside a quadrant.

Global Promotion and Demotion Using PDC

The HDL source file or schematic is the preferred place for defining which signals should be assigned to a clock network using clock macro instantiation. This method is preferred because it is guaranteed to be honored by the synthesis tools and Designer software and stop any replication on this net by the synthesis tool. Note that a signal with fanout may have logic replication if it is not promoted to global during synthesis. In that case, the user cannot promote that signal to global using PDC. See Synplicity Help for details on using this attribute. To help you with global management, Designer allows you to promote a signal to a global network or demote a global macro to a regular macro from the user netlist using the compile options and/or PDC commands.

The following are the PDC constraints you can use to promote a signal to a global network:

1. PDC syntax to promote a regular net to a chip global clock:

```
assign_global_clock -net netname
```

The following will happen during promotion of a regular signal to a global network:

- If the net is external, the net will be driven by a CLKINT inserted automatically by Compile.
- The I/O macro will not be changed to CLKBUF macros.
- If the net is an internal net, the net will be driven by a CLKINT inserted automatically by Compile.

2. PDC syntax to promote a net to a quadrant clock:

```
assign_local_clock -net netname -type quadrant UR|UL|LR|LL
```

This follows the same rule as the chip global clock network.

The following PDC command demotes the clock nets to regular nets.

```
unassign_global_clock -net netname
```

| Date | Changes | Page |
|-----------------------------------|--|--------|
| v1.1 (March 2008) | The "Global Architecture" section was updated to include the IGLOO PLUS family. The bullet was revised to include that the west CCC does not contain a PLL core in 15 k and 30 k devices. Instances of "A3P030 and AGL030 devices" were replaced with "15 k and 30 k gate devices." | 47 |
| v1.1 (continued) | Table 3-1 • Flash-Based FPGAs and the accompanying text was updated to include the IGLOO PLUS family. The "IGLOO Terminology" section and "ProASIC3 Terminology" section are new. | 48 |
| | The "VersaNet Global Network Distribution" section, "Spine Architecture" section, the note in Figure 3-1 • Overview of VersaNet Global Network and Device Architecture, and the note in Figure 3-3 • Simplified VersaNet Global Network (60 k gates and above) were updated to include mention of 15 k gate devices. | 49, 50 |
| | Table 3-4 • Globals/Spines/Rows for IGLOO and ProASIC3 Devices was updated to add the A3P015 device, and to revise the values for clock trees, globals/spines per tree, and globals/spines per device for the A3P030 and AGL030 devices. | 57 |
| | Table 3-5 • Globals/Spines/Rows for IGLOO PLUS Devices is new. | 58 |
| | CLKBUF_LVCMOS12 was added to Table 3-9 • I/O Standards within CLKBUF. | 63 |
| | The "User's Guides" section was updated to include the three different I/O Structures chapters for ProASIC3 and IGLOO device families. | 74 |
| v1.0 (January 2008) | Figure 3-3 • Simplified VersaNet Global Network (60 k gates and above) was updated. | 50 |
| | The "Naming of Global I/Os" section was updated. | 51 |
| | The "Using Global Macros in Synplicity" section was updated. | 66 |
| | The "Global Promotion and Demotion Using PDC" section was updated. | 67 |
| | The "Designer Flow for Global Assignment" section was updated. | 69 |
| | The "Simple Design Example" section was updated. | 71 |
| 51900087-0/1.05 (January 2005) | Table 3-4 • Globals/Spines/Rows for IGLOO and ProASIC3 Devices was updated. | 57 |

4 – Clock Conditioning Circuits in Low Power Flash Devices and Mixed Signal FPGAs

Introduction

This document outlines the following device information: Clock Conditioning Circuit (CCC) features, PLL core specifications, functional descriptions, software configuration information, detailed usage information, recommended board-level considerations, and other considerations concerning clock conditioning circuits and global networks in low power flash devices or mixed signal FPGAs.

Overview of Clock Conditioning Circuitry

In Fusion, IGLOO, and ProASIC3 devices, the CCCs are used to implement frequency division, frequency multiplication, phase shifting, and delay operations. The CCCs are available in six chip locations—each of the four chip corners and the middle of the east and west chip sides. For device-specific variations, refer to the "Device-Specific Layout" section on page 94.

The CCC is composed of the following:

- PLL core
- 3 phase selectors
- 6 programmable delays and 1 fixed delay that advances/delays phase
- 5 programmable frequency dividers that provide frequency multiplication/division (not shown in Figure 4-6 on page 87 because they are automatically configured based on the user's required frequencies)
- 1 dynamic shift register that provides CCC dynamic reconfiguration capability

Figure 4-1 provides a simplified block diagram of the physical implementation of the building blocks in each of the CCCs.

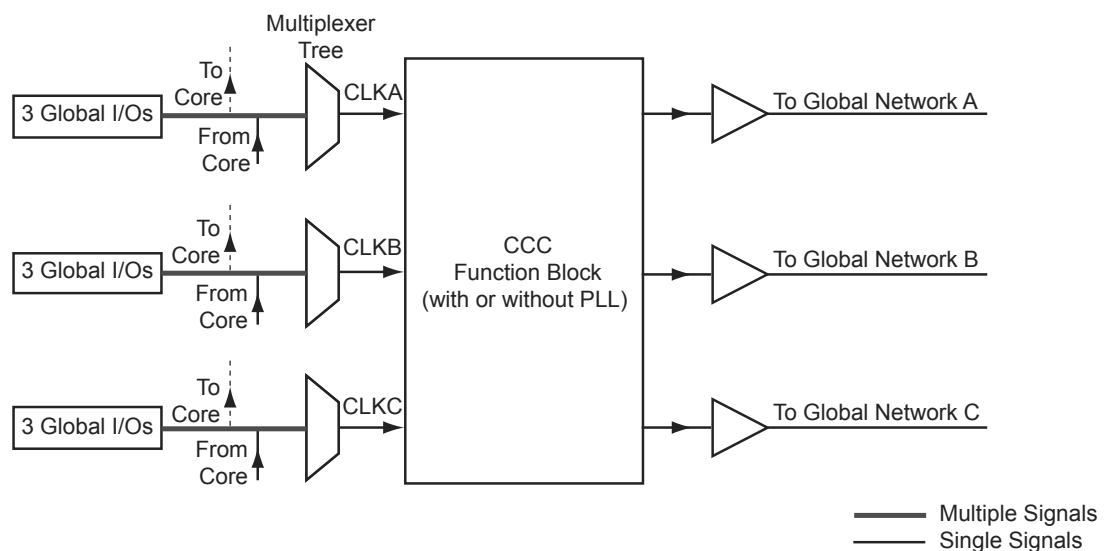
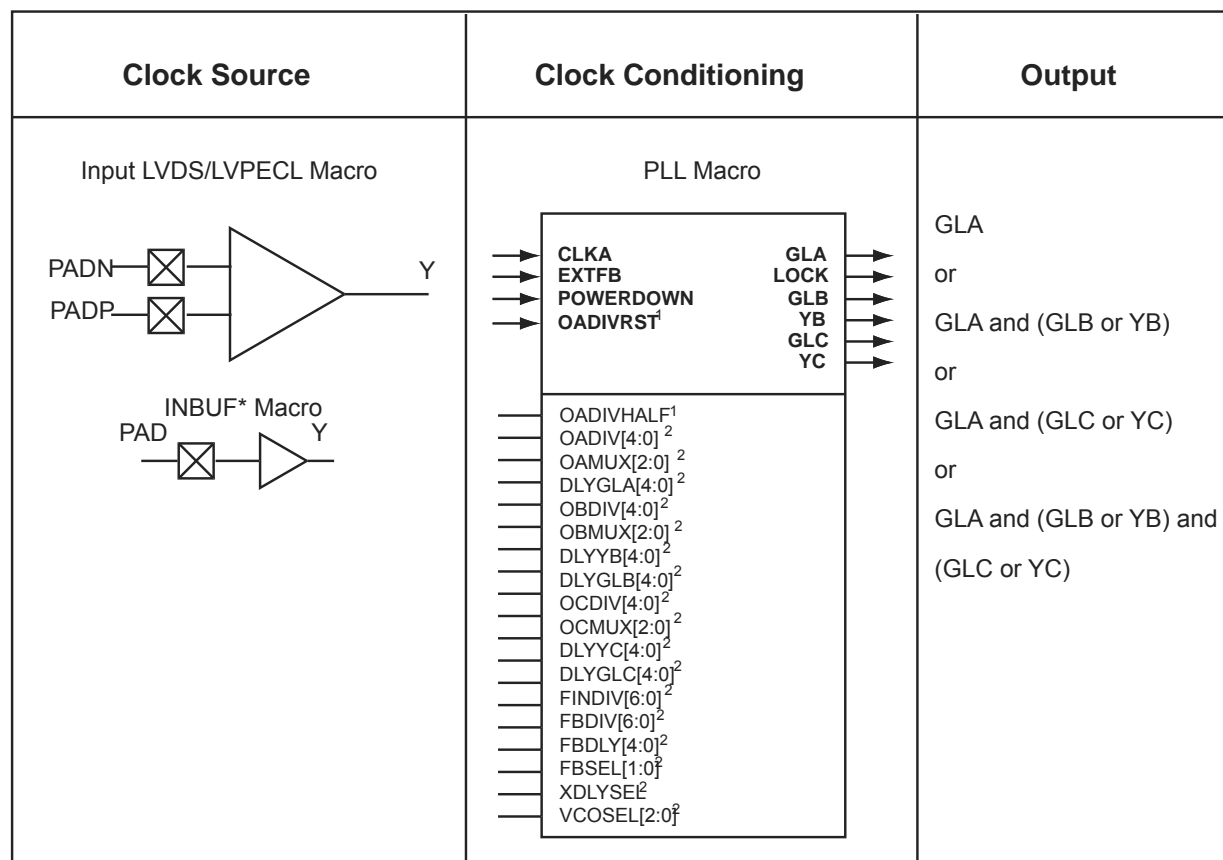


Figure 4-1 • Overview of the CCCs Offered in Fusion, IGLOO, and ProASIC3

Global Buffers with PLL Function

Clocks requiring frequency synthesis or clock adjustments can utilize the PLL core before connecting to the global / quadrant global networks. A maximum of 18 CCC global buffers can be instantiated in a device—three per CCC and up to six CCCs per device. Each PLL core can generate up to three global/quadrant clocks, while a clock delay element provides one.

The PLL functionality of the clock conditioning block is supported by the PLL macro.



Notes:

1. For Fusion only.
2. Refer to the IGLOO, ProASIC3, SmartFusion, and Fusion Macro Library Guide for more information.
3. For INBUF* driving a PLL macro or CLKDLY macro, the I/O will be hard-routed to the CCC; i.e., will be placed by software to a dedicated Global I/O.
4. IGLOO nano and ProASIC3 nano devices do not support differential inputs.

Figure 4-4 • CCC Options: Global Buffers with PLL

The PLL macro provides five derived clocks (three independent) from a single reference clock. The PLL macro also provides power-down input and lock output signals. The additional inputs shown on the macro are configuration settings, which are configured through the use of SmartGen. For manual setting of these bits refer to the *IGLOO, ProASIC3, SmartFusion, and Fusion Macro Library Guide* for details.

Figure 4-6 on page 87 illustrates the various clock output options and delay elements.

global assignments are not allocated properly. See the "Physical Constraints for Quadrant Clocks" section for information on assigning global signals to the quadrant clock networks.

Promoted global signals will be instantiated with CLKINT macros to drive these signals onto the global network. This is automatically done by Designer when the Auto-Promotion option is selected. If the user wishes to assign the signals to the quadrant globals instead of the default chip globals, this can be done by using ChipPlanner, by declaring a physical design constraint (PDC), or by importing a PDC file.

Physical Constraints for Quadrant Clocks

If it is necessary to promote global clocks (CLKBUF, CLKINT, PLL, CLKDLY) to quadrant clocks, the user can define PDCs to execute the promotion. PDCs can be created using PDC commands (pre-compile) or the MultiView Navigator (MVN) interface (post-compile). The advantage of using the PDC flow over the MVN flow is that the Compile stage is able to automatically promote any regular net to a global net before assigning it to a quadrant. There are three options to place a quadrant clock using PDC commands:

- Place a clock core (not hardwired to an I/O) into a quadrant clock location.
- Place a clock core (hardwired to an I/O) into an I/O location (set_io) or an I/O module location (set_location) that drives a quadrant clock location.
- Assign a net driven by a regular net or a clock net to a quadrant clock using the following command:

```
assign_local_clock -net <net name> -type quadrant <quadrant clock region>
```

where

<net name> is the name of the net assigned to the local user clock region.

<quadrant clock region> defines which quadrant the net should be assigned to. Quadrant clock regions are defined as UL (upper left), UR (upper right), LL (lower left), and LR (lower right).

Note: If the net is a regular net, the software inserts a CLKINT buffer on the net.

For example:

```
assign_local_clock -net localReset -type quadrant UR
```

Keep in mind the following when placing quadrant clocks using MultiView Navigator:

Hardwired I/O–Driven CCCs

- Find the associated clock input port under the Ports tab, and place the input port at one of the Gmn* locations using PinEditor or I/O Attribute Editor, as shown in Figure 4-32.

Figure 4-32 • Port Assignment for a CCC with Hardwired I/O Clock Input

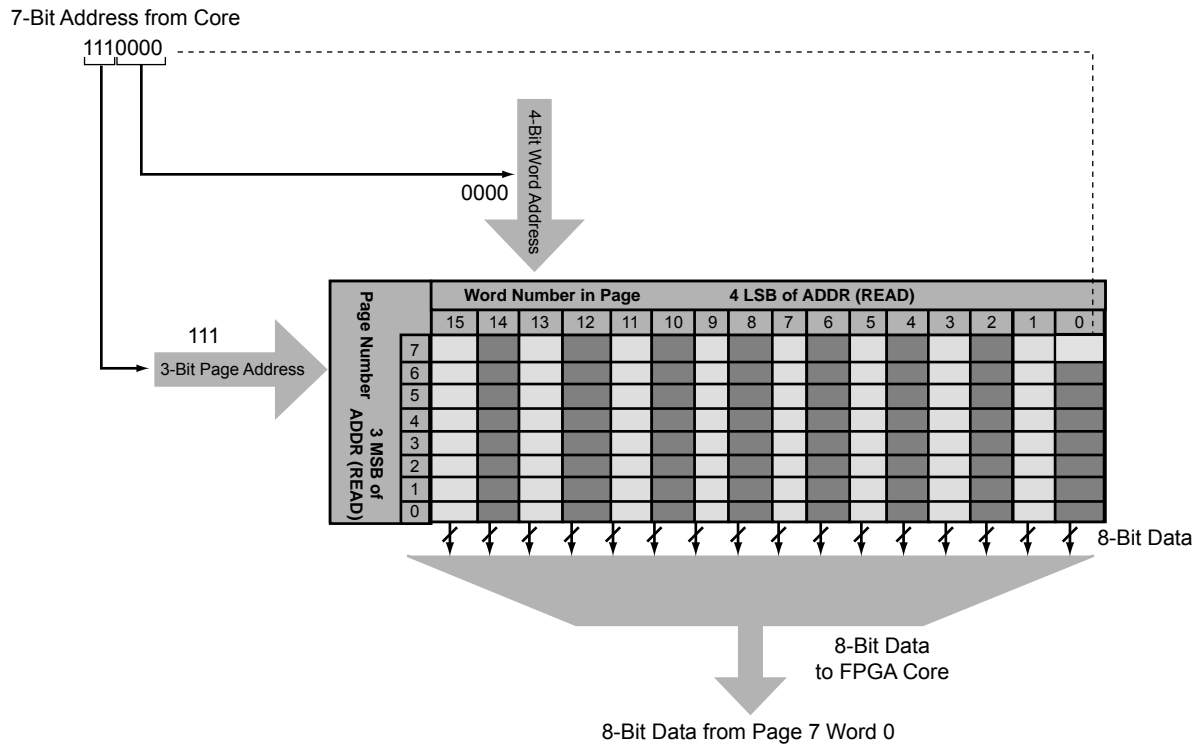


Figure 5-7 • Accessing FlashROM Using FPGA Core

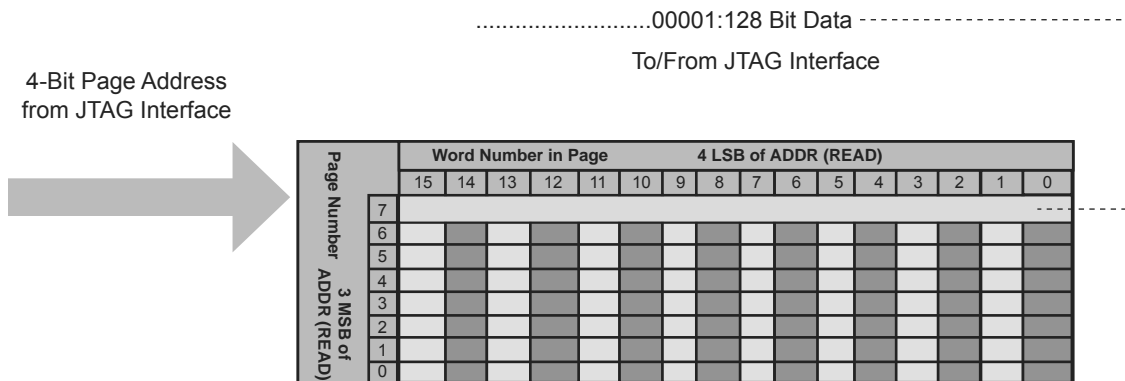
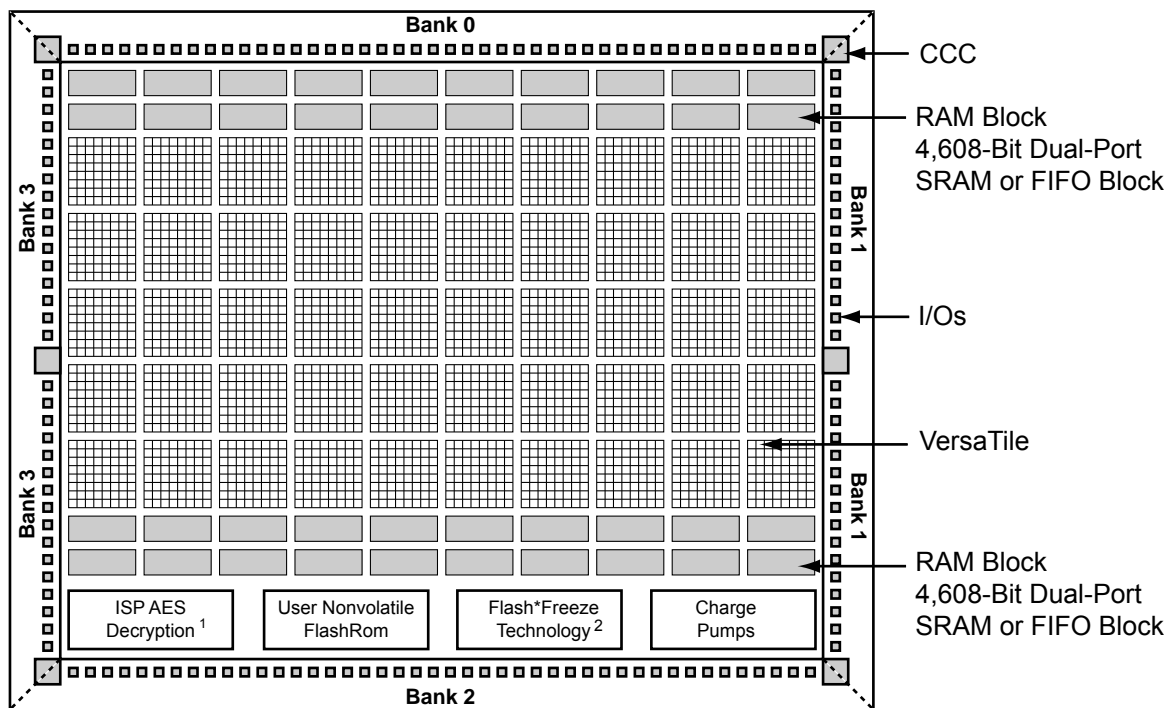


Figure 5-8 • Accessing FlashROM Using JTAG Port



Notes:

1. AES decryption not supported in 30 k gate devices and smaller.
2. Flash*Freeze is supported in all IGLOO devices and the ProASIC3L devices.

Figure 6-1 • IGLOO and ProASIC3 Device Architecture Overview

Conclusion

Fusion, IGLOO, and ProASIC3 devices provide users with extremely flexible SRAM blocks for most design needs, with the ability to choose between an easy-to-use dual-port memory or a wide-word two-port memory. Used with the built-in FIFO controllers, these memory blocks also serve as highly efficient FIFOs that do not consume user gates when implemented. The SmartGen core generator provides a fast and easy way to configure these memory elements for use in designs.

List of Changes

The following table lists critical changes that were made in each revision of the chapter.

| Date | Changes | Page |
|-------------------------|---|------|
| August 2012 | The note connected with Figure 6-3 • Supported Basic RAM Macros, regarding RAM4K9, was revised to explain that it applies only to part numbers of certain revisions and earlier (SAR 29574). | 152 |
| July 2010 | This chapter is no longer published separately with its own part number and version but is now part of several FPGA fabric user's guides. | N/A |
| v1.5 (December 2008) | IGLOO nano and ProASIC3 nano devices were added to Table 6-1 • Flash-Based FPGAs. | 150 |
| | IGLOO nano and ProASIC3 nano devices were added to Figure 6-8 • Interfacing TAP Ports and SRAM Blocks. | 164 |
| v1.4 (October 2008) | The "SRAM/FIFO Support in Flash-Based Devices" section was revised to include new families and make the information more concise. | 150 |
| | The "SRAM and FIFO Architecture" section was modified to remove "IGLOO and ProASIC3E" from the description of what the memory block includes, as this statement applies to all memory blocks. | 151 |
| | Wording in the "Clocking" section was revised to change "IGLOO and ProASIC3 devices support inversion" to "Low power flash devices support inversion." The reference to IGLOO and ProASIC3 development tools in the last paragraph of the section was changed to refer to development tools in general. | 157 |
| | The "ESTOP and FSTOP Usage" section was updated to refer to FIFO counters in devices in general rather than only IGLOO and ProASIC3E devices. | 160 |
| v1.3 (August 2008) | The note was removed from Figure 6-7 • RAM Block with Embedded FIFO Controller and placed in the WCLK and RCLK description. | 158 |
| | The "WCLK and RCLK" description was revised. | 159 |
| v1.2 (June 2008) | The following changes were made to the family descriptions in Table 6-1 • Flash-Based FPGAs: <ul style="list-style-type: none"> ProASIC3L was updated to include 1.5 V. The number of PLLs for ProASIC3E was changed from five to six. | 150 |
| v1.1 (March 2008) | The "Introduction" section was updated to include the IGLOO PLUS family. | 147 |
| | The "Device Architecture" section was updated to state that 15 k gate devices do not support SRAM and FIFO. | 147 |
| | The first note in Figure 6-1 • IGLOO and ProASIC3 Device Architecture Overview was updated to include mention of 15 k gate devices, and IGLOO PLUS was added to the second note. | 149 |

Features Supported on Every I/O

Table 7-5 lists all features supported by transmitter/receiver for single-ended and differential I/Os. Table 7-6 on page 180 lists the performance of each I/O technology.

Table 7-5 • I/O Features

| Feature | Description |
|---|--|
| All I/O | <ul style="list-style-type: none"> • High performance (Table 7-6 on page 180) • Electrostatic discharge (ESD) protection • I/O register combining option |
| Single-Ended Transmitter Features | <ul style="list-style-type: none"> • Hot-swap: <ul style="list-style-type: none"> – 30K gate devices: hot-swap in every mode – All other IGLOO and ProASIC3 devices: no hot-swap • Output slew rate: 2 slew rates (except 30K gate devices) • Weak pull-up and pull-down resistors • Output drive: 3 drive strengths • Programmable output loading • Skew between output buffer enable/disable time: 2 ns delay on rising edge and 0 ns delay on falling edge (see the "Selectable Skew between Output Buffer Enable and Disable Times" section on page 199 for more information) • LVTTTL/LVCMOS 3.3 V outputs compatible with 5 V TTL inputs |
| Single-Ended Receiver Features | <ul style="list-style-type: none"> • 5 V–input–tolerant receiver (Table 7-12 on page 193) • Separate ground plane for GNDQ pin and power plane for VMV pin are used for input buffer to reduce output-induced noise. |
| Differential Receiver Features—250K through 1M Gate Devices | <ul style="list-style-type: none"> • Separate ground plane for GNDQ pin and power plane for VMV pin are used for input buffer to reduce output-induced noise. |
| CMOS-Style LVDS, B-LVDS, M-LVDS, or LVPECL Transmitter | <ul style="list-style-type: none"> • Two I/Os and external resistors are used to provide a CMOS-style LVDS, DDR LVDS, B-LVDS, and M-LVDS/LVPECL transmitter solution. • High slew rate • Weak pull-up and pull-down resistors • Programmable output loading |

Simultaneously Switching Outputs (SSOs) and Printed Circuit Board Layout

Each I/O voltage bank has a separate ground and power plane for input and output circuits (VMV/GNDQ for input buffers and VCCI/GND for output buffers). This isolation is necessary to minimize simultaneous switching noise from the input and output (SSI and SSO). The switching noise (ground bounce and power bounce) is generated by the output buffers and transferred into input buffer circuits, and vice versa.

Since voltage bounce originates on the package inductance, the VMV and VCCI supplies have separate package pin assignments. For the same reason, GND and GNDQ also have separate pin assignments.

The VMV and VCCI pins must be shorted to each other on the board. Also, the GND and GNDQ pins must be shorted to each other on the board. This will prevent unwanted current draw from the power supply.

SSOs can cause signal integrity problems on adjacent signals that are not part of the SSO bus. Both inductive and capacitive coupling parasitics of bond wires inside packages and of traces on PCBs will transfer noise from SSO busses onto signals adjacent to those busses. Additionally, SSOs can produce ground bounce noise and VCCI dip noise. These two noise types are caused by rapidly changing currents through GND and VCCI package pin inductances during switching activities (EQ 2 and EQ 3).

$$\text{Ground bounce noise voltage} = L(\text{GND}) \times di/dt$$

EQ 2

$$\text{VCCI dip noise voltage} = L(\text{VCCI}) \times di/dt$$

EQ 3

Any group of four or more input pins switching on the same clock edge is considered an SSO bus. The shielding should be done both on the board and inside the package unless otherwise described.

In-package shielding can be achieved in several ways; the required shielding will vary depending on whether pins next to the SSO bus are LVTTTL/LVCMOS inputs, LVTTTL/LVCMOS outputs, or GTL/SSTL/HSTL/LVDS/LVPECL inputs and outputs. Board traces in the vicinity of the SSO bus have to be adequately shielded from mutual coupling and inductive noise that can be generated by the SSO bus. Also, noise generated by the SSO bus needs to be reduced inside the package.

PCBs perform an important function in feeding stable supply voltages to the IC and, at the same time, maintaining signal integrity between devices.

Key issues that need to be considered are as follows:

- Power and ground plane design and decoupling network design
- Transmission line reflections and terminations

For extensive data per package on the SSO and PCB issues, refer to the "ProASIC3/E SSO and Pin Placement and Guidelines" chapter of the *ProASIC3 FPGA Fabric User's Guide*.

Power-Up Behavior

Low power flash devices are power-up/-down friendly; i.e., no particular sequencing is required for power-up and power-down. This eliminates extra board components for power-up sequencing, such as a power-up sequencer.

During power-up, all I/Os are tristated, irrespective of I/O macro type (input buffers, output buffers, I/O buffers with weak pull-ups or weak pull-downs, etc.). Once I/Os become activated, they are set to the user-selected I/O macros. Refer to the "Power-Up/-Down Behavior of Low Power Flash Devices" section on page 373 for details.

Drive Strength

Low power flash devices have up to seven programmable output drive strengths. The user can select the drive strength of a particular output in the I/O Attribute Editor or can instantiate a specialized I/O macro, such as OUTBUF_S_12 (slew = low, out_drive = 12 mA).

The maximum available drive strength is 24 mA per I/O. Though no I/O should be forced to source or sink more than 24 mA indefinitely, I/Os may handle a higher amount of current (refer to the device IBIS model for maximum source/sink current) during signal transition (AC current). Every device package has its own power dissipation limit; hence, power calculation must be performed accurately to determine how much current can be tolerated per I/O within that limit.

I/O Interfacing

Low power flash devices are 5 V–input– and 5 V–output–tolerant if certain I/O standards are selected (refer to the "5 V Input and Output Tolerance" section on page 232). Along with other low-voltage I/O macros, this 5 V tolerance makes these devices suitable for many types of board component interfacing.

Table 8-19 shows some high-level interfacing examples using low power flash devices.

Table 8-19 • High-Level Interface Examples

| Interface | Clock | | I/O | | | |
|--------------------|--------------|-----------------|-------|--------------|--------------|------------|
| | Type | Frequency | Type | Signals In | Signals Out | Data I/O |
| GM | Src Sync | 125 MHz | LVTTL | 8 | 8 | 125 Mbps |
| TBI | Src Sync | 125 MHz | LVTTL | 10 | 10 | 125 Mbps |
| XSBI | Src Sync | 644 MHz | LVDS | 16 | 16 | 644 Mbps |
| XGMI | Src Sync DDR | 156 MHz | HSTL1 | 32 | 32 | 312 Mbps |
| FlexBus 3 | Sys Sync | 104 MHz | LVTTL | ≤ 32 | ≤ 32 | ≤ 104 |
| Pos-PHY3/SPI-3 | Sys Sync | 104 | LVTTL | 8,16,32 | 8,16,32 | ≤ 104 Mbps |
| FlexBus 4/SPI-4.1 | Src Sync | 200 MHz | HSTL1 | 16,64 | 16,64 | 200 Mbps |
| Pos-PHY4/SPI-4.2 | Src Sync DDR | ≥ 311 MHz | LVDS | 16 | 16 | ≥ 622 Mbps |
| SFI-4.1 | Src Sync | 622 MHz | LVDS | 16 | 16 | 622 Mbps |
| CSIX L1 | Sys Sync | ≤ 250 MHz | HSTL1 | 32,64,96,128 | 32,64,96,128 | ≤ 250 Mbps |
| Hyper Transport | Sys Sync DDR | ≤ 800 MHz | LVDS | 2,4,8,16 | 2,4,8,16 | ≤ 1.6 Gbps |
| Rapid I/O Parallel | Sys Sync DDR | 250 MHz – 1 GHz | LVDS | 8,16 | 8,16 | ≤ 2 Gbps |
| Star Fabric | CDR | | LVDS | 4 | 4 | 622 Mbps |

Note: Sys Sync = System Synchronous Clocking, Src Sync = Source Synchronous Clocking, and CDR = Clock and Data Recovery.

9 – I/O Software Control in Low Power Flash Devices

Fusion, IGLOO, and ProASIC3 I/Os provide more design flexibility, allowing the user to control specific features by enabling certain I/O standards. Some features are selectable only for certain I/O standards, whereas others are available for all I/O standards. For example, slew control is not supported by differential I/O standards. Conversely, I/O register combining is supported by all I/O standards. For detailed information about which I/O standards and features are available on each device and each I/O type, refer to the I/O Structures section of the handbook for the device you are using.

Figure 9-1 shows the various points in the software design flow where a user can provide input or control of the I/O selection and parameters. A detailed description is provided throughout this document.

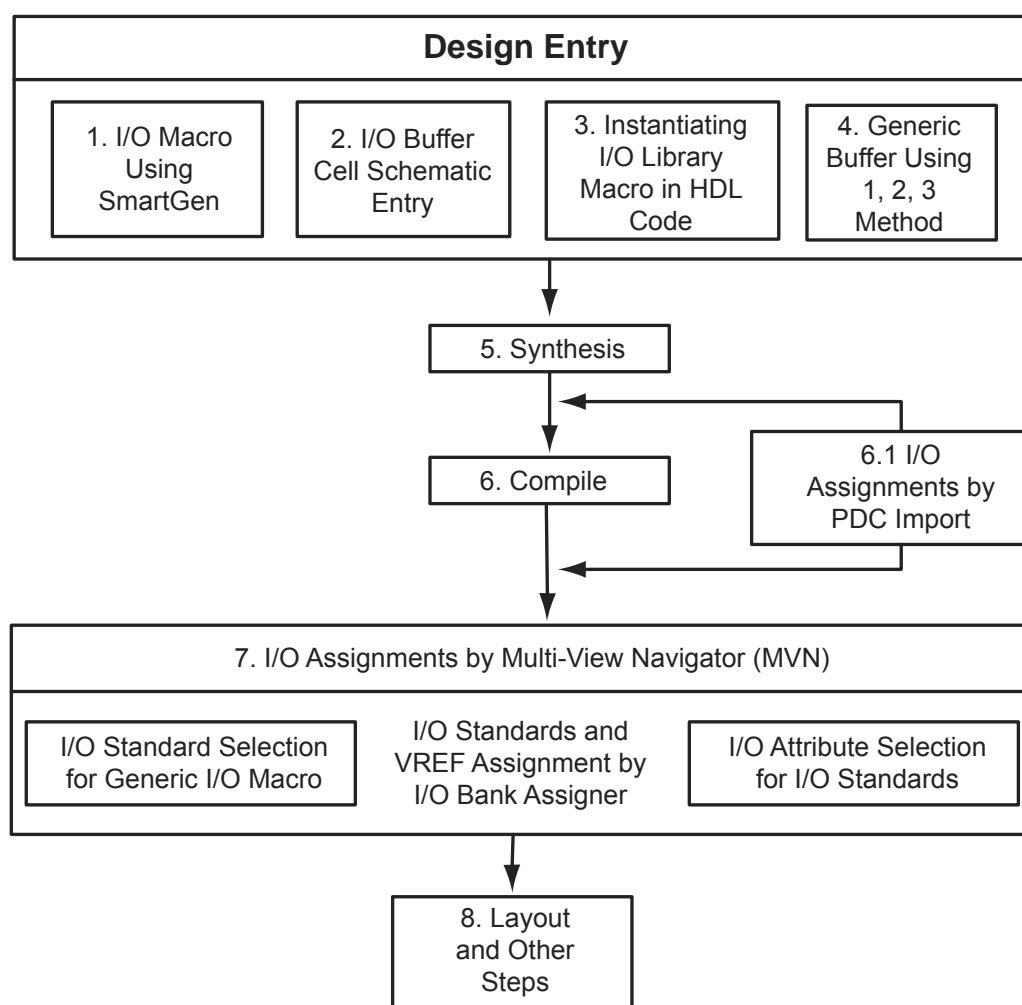


Figure 9-1 • User I/O Assignment Flow Chart

12 – Security in Low Power Flash Devices

Security in Programmable Logic

The need for security on FPGA programmable logic devices (PLDs) has never been greater than today. If the contents of the FPGA can be read by an external source, the intellectual property (IP) of the system is vulnerable to unauthorized copying. Fusion, IGLOO, and ProASIC3 devices contain state-of-the-art circuitry to make the flash-based devices secure during and after programming. Low power flash devices have a built-in 128-bit Advanced Encryption Standard (AES) decryption core (except for 30 k gate devices and smaller). The decryption core facilitates secure in-system programming (ISP) of the FPGA core array fabric, the FlashROM, and the Flash Memory Blocks (FBs) in Fusion devices. The FlashROM, Flash Blocks, and FPGA core fabric can be programmed independently of each other, allowing the FlashROM or Flash Blocks to be updated without the need for change to the FPGA core fabric.

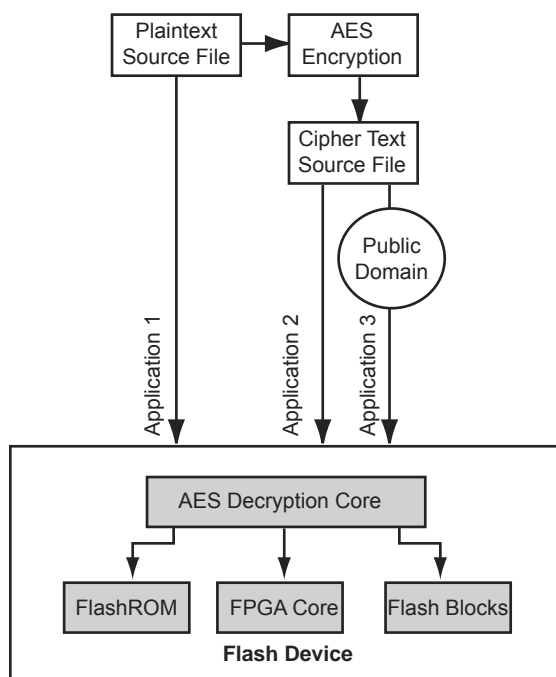
Microsemi has incorporated the AES decryption core into the low power flash devices and has also included the Microsemi flash-based lock technology, FlashLock.[®] Together, they provide leading-edge security in a programmable logic device. Configuration data loaded into a device can be decrypted prior to being written to the FPGA core using the AES 128-bit block cipher standard. The AES encryption key is stored in on-chip, nonvolatile flash memory.

This document outlines the security features offered in low power flash devices, some applications and uses, as well as the different software settings for each application.

Figure 12-1 • Overview on Security

Security in Action

This section illustrates some applications of the security advantages of Microsemi's devices (Figure 12-6).



Note: Flash blocks are only used in Fusion devices

Figure 12-6 • Security Options

Microsemi's Flash Families Support Voltage Switching Circuit

The flash FPGAs listed in Table 14-1 support the voltage switching circuit feature and the functions described in this document.

Table 14-1 • Flash-Based FPGAs Supporting Voltage Switching Circuit

| Series | Family* | Description |
|----------|----------------------|---|
| IGLOO | IGLOO | Ultra-low power 1.2 V to 1.5 V FPGAs with Flash*Freeze technology |
| | IGLOOe | Higher density IGLOO FPGAs with six PLLs and additional I/O standards |
| | IGLOO nano | The industry's lowest-power, smallest-size solution |
| | IGLOO PLUS | IGLOO FPGAs with enhanced I/O capabilities |
| ProASIC3 | ProASIC3L | ProASIC3 FPGAs supporting 1.2 V to 1.5 V with Flash*Freeze technology |
| | RT ProASIC3 | Radiation-tolerant RT3PE600L and RT3PE3000L |
| | Military ProASIC3/EL | Military temperature A3PE600L, A3P1000, and A3PE3000L |

Note: *The device names link to the appropriate datasheet, including product brief, DC and switching characteristics, and packaging information.

IGLOO Terminology

In documentation, the terms IGLOO series and IGLOO devices refer to all of the IGLOO devices as listed in Table 14-1. Where the information applies to only one product line or limited devices, these exclusions will be explicitly stated.

ProASIC3 Terminology

In documentation, the terms ProASIC3 series and ProASIC3 devices refer to all of the ProASIC3 devices as listed in Table 14-1. Where the information applies to only one product line or limited devices, these exclusions will be explicitly stated.

To further understand the differences between the IGLOO and ProASIC3 devices, refer to the *Industry's Lowest Power FPGAs Portfolio*.

List of Changes

The following table lists critical changes that were made in each revision of the chapter.

| Date | Changes | Page |
|------------------------|---|------|
| July 2010 | This chapter is no longer published separately with its own part number and version but is now part of several FPGA fabric user's guides. | N/A |
| v1.1 (October 2008) | The "Introduction" was revised to include information about the core supply voltage range of operation in V2 devices. | 341 |
| | IGLOO nano device support was added to Table 14-1 • Flash-Based FPGAs Supporting Voltage Switching Circuit. | 342 |
| | The "Circuit Description" section was updated to include IGLOO PLUS core operation from 1.2 V to 1.5 V in 50 mV increments. | 343 |
| v1.0 (August 2008) | The "Microsemi's Flash Families Support Voltage Switching Circuit" section was revised to include new families and make the information more concise. | 342 |

Microprocessor Programming Support in Flash Devices

The flash-based FPGAs listed in Table 15-1 support programming with a microprocessor and the functions described in this document.

Table 15-1 • Flash-Based FPGAs

| Series | Family* | Description |
|----------|----------------------|---|
| IGLOO | IGLOO | Ultra-low power 1.2 V to 1.5 V FPGAs with Flash*Freeze technology |
| | IGLOOe | Higher density IGLOO FPGAs with six PLLs and additional I/O standards |
| | IGLOO nano | The industry's lowest-power, smallest-size solution |
| | IGLOO PLUS | IGLOO FPGAs with enhanced I/O capabilities |
| ProASIC3 | ProASIC3 | Low power, high-performance 1.5 V FPGAs |
| | ProASIC3E | Higher density ProASIC3 FPGAs with six PLLs and additional I/O standards |
| | ProASIC3 nano | Lowest-cost solution with enhanced I/O capabilities |
| | ProASIC3L | ProASIC3 FPGAs supporting 1.2 V to 1.5 V with Flash*Freeze technology |
| | RT ProASIC3 | Radiation-tolerant RT3PE600L and RT3PE3000L |
| | Military ProASIC3/EL | Military temperature A3PE600L, A3P1000, and A3PE3000L |
| | Automotive ProASIC3 | ProASIC3 FPGAs qualified for automotive applications |
| Fusion | Fusion | Mixed signal FPGA integrating ProASIC3 FPGA fabric, programmable analog block, support for ARM® Cortex™-M1 soft processors, and flash memory into a monolithic device |

Note: *The device names link to the appropriate datasheet, including product brief, DC and switching characteristics, and packaging information.

IGLOO Terminology

In documentation, the terms IGLOO series and IGLOO devices refer to all of the IGLOO devices as listed in Table 15-1. Where the information applies to only one device or limited devices, these exclusions will be explicitly stated.

ProASIC3 Terminology

In documentation, the terms ProASIC3 series and ProASIC3 devices refer to all of the ProASIC3 devices as listed in Table 15-1. Where the information applies to only one device or limited devices, these exclusions will be explicitly stated.

To further understand the differences between the IGLOO and ProASIC3 devices, refer to the *Industry's Lowest Power FPGAs Portfolio*.